BPW 34 SR

DIL SMT

Silicon PIN Photodiode





Applications

- Rain Sensors

Features:

- Package: clear epoxy
- Corrosion Robustness Class: 3B
- Qualifications: The product qualification test plan is based on the guidelines of AEC-Q101-REV-C,
 Stress Test Qualification for Automotive Grade Discrete Semiconductors.
- ESD: 2 kV acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 2)
- Suitable for reflow soldering
- Especially suitable for applications from 400 nm to 1100 nm
- Short switching time (typ. 20 ns)
- DIL plastic package with high packing density

Ordering Information

Туре	Photocurrent 1)	Photocurrent	Ordering Code
		typ.	
	$E_v = 1000 \text{ lx}$; Std. Light A; $V_R = 5 \text{ V}$	$E_v = 1000 \text{ lx}$; Std. Light A; $V_R = 5 \text{ V}$	
	I_P	I _P	
BPW 34 SR-Z	≥ 55.0 µA	80 μΑ	Q65110A2701



BPW 34 SR

Maximum Ratings			
Parameter	Symbol		Values
Operating Temperature	T _{op}	min. max.	-40 °C 100 °C
Storage temperature	T _{stg}	min.	-40 °C
Reverse voltage	V_R	max.	32 V
Total power dissipation	P _{tot}	max.	150 mW
ESD withstand voltage acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 2)	V_{ESD}	max.	2 kV



Characteristics

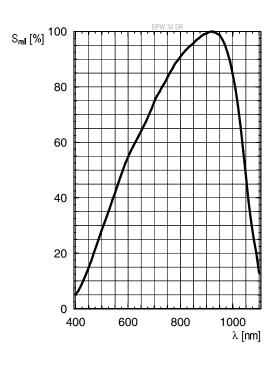
T_A = 25 °C

Parameter	Symbol		Values
Wavelength of max sensitivity	$\lambda_{S\;max}$	typ.	920 nm
Spectral range of sensitivity	λ _{10%}	typ.	420 1120 nm
Radiant sensitive area	А	typ.	7.02 mm²
Dimensions of active chip area	LxW	typ.	2.65 x 2.65 mm x mm
Half angle	φ	typ.	60 °
Dark current V _R = 10 V	I _R	typ. max.	2 nA 30 nA
Spectral sensitivity of the chip $\lambda = 850 \text{ nm}$	S_{λ}	typ.	0.62 A / W
Quantum yield of the chip $\lambda = 850 \text{ nm}$	η	typ.	0.90 Electrons / Photon
Open-circuit voltage $E_v = 1000 \text{ lx}$; Std. Light A; $V_R = 0 \text{ V}$	V _o	min. typ.	300 mV 365 mV
Short-circuit current $E_v = 1000 \text{ lx}$; Std. Light A; $V_R = 0 \text{ V}$	I _{SC}	typ.	80 μΑ
Rise time $V_R = 5 \text{ V}; R_L = 50 \Omega; \lambda = 850 \text{ nm}$	t,	typ.	0.02 μs
Fall time $V_R = 5 \text{ V}; R_L = 50 \Omega; \lambda = 850 \text{ nm}$	t _f	typ.	0.02 μs
Forward voltage I _F = 100 mA; E = 0	V_{F}	typ.	1.3 V
Capacitance $V_R = 0 \text{ V}; f = 1 \text{ MHz}; E = 0$	C ₀	typ.	72 pF
Temperature coefficient of voltage	TC_v	typ.	-2.6 mV / K
Temperature coefficient of short-circuit current Std. Light A	TC ₁	typ.	0.18 % / K
Noise equivalent power $V_R = 10 \text{ V}; \lambda = 850 \text{ nm}$	NEP	typ.	0.041 pW / Hz ^{1/2}
Detection limit $V_R = 5 \text{ V}; \lambda = 850 \text{ nm}$	D*	typ.	6.5e12 cm x Hz ^{1/2} / W



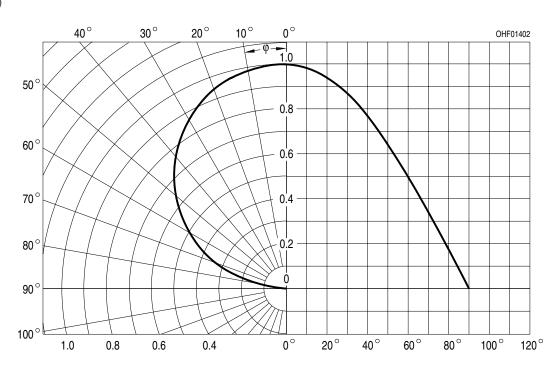
Relative Spectral Sensitivity 2), 3)

 $S_{rel} = f(\lambda)$



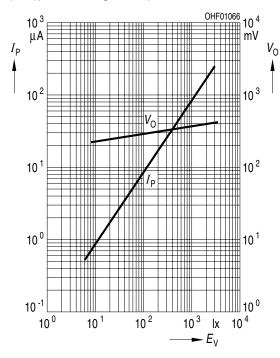
Directional Characteristics 2), 3)

 $S_{rel} = f(\phi)$



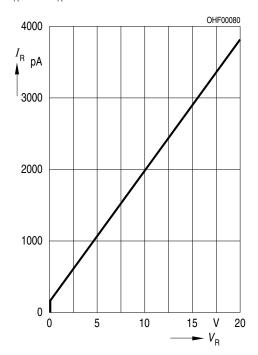
Photocurrent/Open-Circuit Voltage ^{2), 3)}

$$I_P (V_R = 5 \text{ V}) / V_O = f (E_v)$$



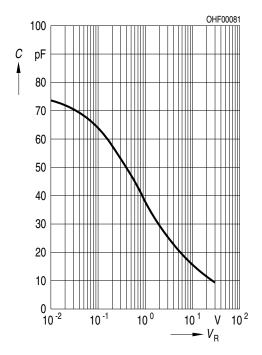
Dark Current 2), 3)

$$I_R = f(V_R); E = 0$$



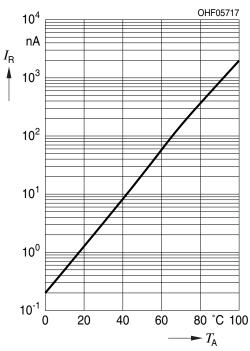
Capacitance 2), 3)

$$C = f(V_R)$$
; $f = 1MHz$; $E = 0$; $T_A = 25$ ° C



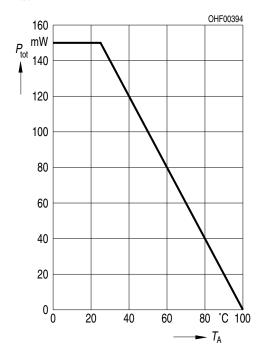
Dark Current 2)

$$I_{R} = f(T_{A}); E = 0; V_{R} = 10 V$$

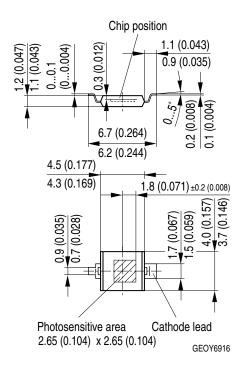


Power Consumption

$$P_{tot} = f(T_A)$$



Dimensional Drawing 4)



Further Information:

Approximate Weight: 43.0 mg

Package marking: Cathode

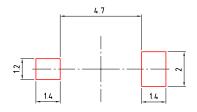
Corrosion test: Class: 3B

Test condition: 40°C / 90 % RH / 15 ppm H₂S / 14 days (stricter than IEC

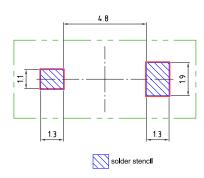
60068-2-43)

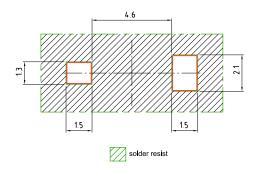


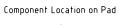
Recommended Solder Pad 4)

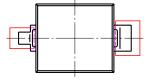








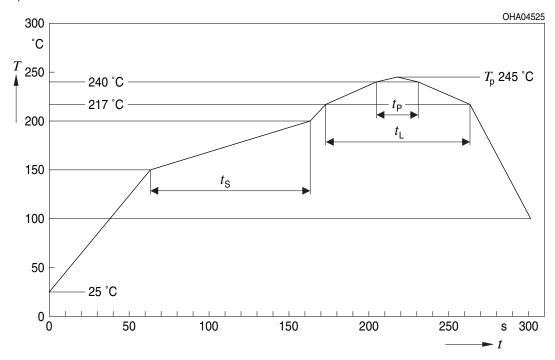




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Reflow Soldering Profile

Product complies to MSL Level 4 acc. to JEDEC J-STD-020E



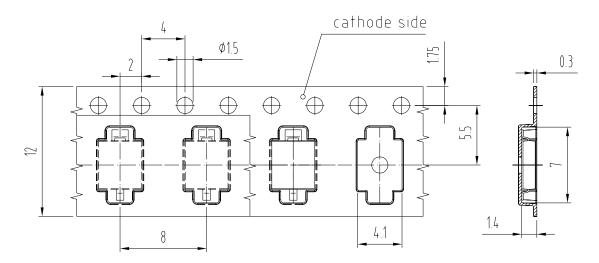
Profile Feature	Symbol	pol Pb-Free (SnAgCu) Assembly			Unit
		Minimum	Recommendation	Maximum	
Ramp-up rate to preheat*)	'		2	3	K/s
25 °C to 150 °C					
Time t _s	t_s	60	100	120	S
T_{Smin} to T_{Smax}					
Ramp-up rate to peak*)			2	3	K/s
T_{Smax} to T_{P}					
Liquidus temperature	T_{L}		217		°C
Time above liquidus temperature	$t_{\scriptscriptstyle \perp}$		80	100	S
Peak temperature	T_{P}		245	260	°C
Time within 5 °C of the specified peak	t _P	10	20	30	S
temperature T _P - 5 K					
Ramp-down rate*			3	6	K/s
T _P to 100 °C					
Time				480	S
25 °C to T _P					

All temperatures refer to the center of the package, measured on the top of the component



 $^{^{\}ast}$ slope calculation DT/Dt: Dt max. 5 s; fulfillment for the whole T-range

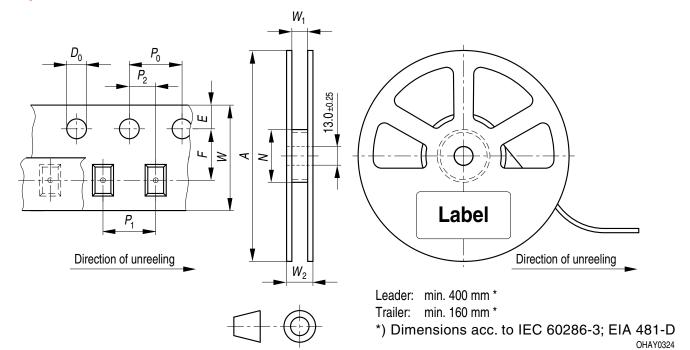
Taping 4)



C63062-A3171-B8-04



Tape and Reel 5)



Reel Dimensions

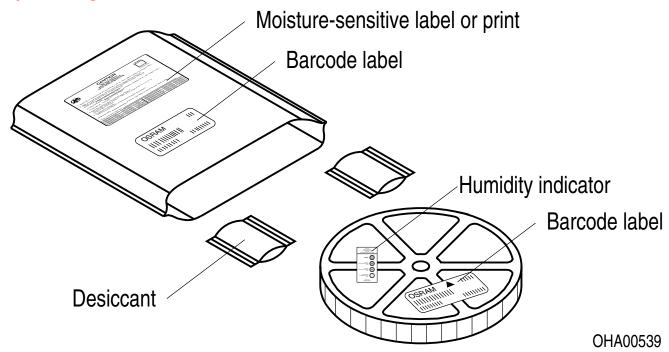
Α	W	N_{\min}	W ₁	W_{2max}	Pieces per PU
180 mm	12 + 0.3 / - 0.1 mm	60 mm	12.4 + 2 mm	18.4 mm	1500



Barcode-Product-Label (BPL)



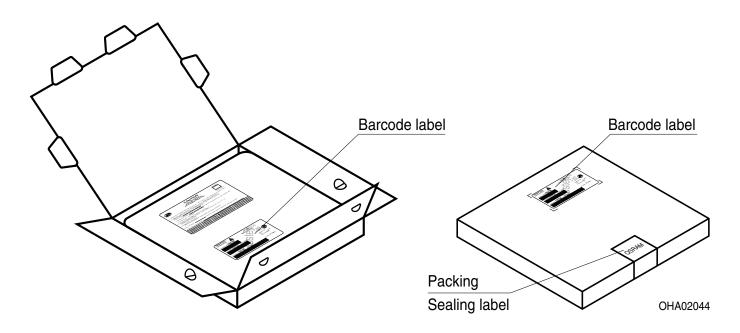
Dry Packing Process and Materials 4)



Moisture-sensitive product is packed in a dry bag containing desiccant and a humidity card according JEDEC-STD-033.



Schematic Transportation Box 4)



Dimensions of Transportation Box

Width	Length	Height
195 ± 5 mm	195 ± 5 mm	30 ± 5 mm



Notes

The evaluation of eye safety occurs according to the standard IEC 62471:2006 (photo biological safety of lamps and lamp systems). Within the risk grouping system of this IEC standard, the device specified in this data sheet falls into the class **exempt group (exposure time 10000 s)**. Under real circumstances (for exposure time, conditions of the eye pupils, observation distance), it is assumed that no endangerment to the eye exists from these devices. As a matter of principle, however, it should be mentioned that intense light sources have a high secondary exposure potential due to their blinding effect. When looking at bright light sources (e.g. headlights), temporary reduction in visual acuity and afterimages can occur, leading to irritation, annoyance, visual impairment, and even accidents, depending on the situation.

Subcomponents of this device contain, in addition to other substances, metal filled materials including silver. Metal filled materials can be affected by environments that contain traces of aggressive substances. Therefore, we recommend that customers minimize device exposure to aggressive substances during storage, production, and use. Devices that showed visible discoloration when tested using the described tests above did show no performance deviations within failure limits during the stated test duration. Respective failure limits are described in the IEC60810.

For further application related information please visit www.osram-os.com/appnotes



Disclaimer

Attention please!

The information describes the type of component and shall not be considered as assured characteristics. Terms of delivery and rights to change design reserved. Due to technical requirements components may contain dangerous substances.

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Packing

Please use the recycling operators known to you. We can also help you – get in touch with your nearest sales office. By agreement we will take packing material back, if it is sorted. You must bear the costs of transport. For packing material that is returned to us unsorted or which we are not obliged to accept, we shall have to invoice you for any costs incurred.

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Glossary

- Photocurrent: The photocurrent values are measured (by irradiating the devices with a homogenous light source and applying a voltage to the device) with a tolerance of ±11 %.
- Typical Values: Due to the special conditions of the manufacturing processes of semiconductor devices, the typical data or calculated correlations of technical parameters can only reflect statistical figures. These do not necessarily correspond to the actual parameters of each single product, which could differ from the typical data and calculated correlations or the typical characteristic line. If requested, e.g. because of technical improvements, these typ. data will be changed without any further notice.
- Testing temperature: TA = 25°C (unless otherwise specified)
- Tolerance of Measure: Unless otherwise noted in drawing, tolerances are specified with ±0.1 and dimensions are specified in mm.
- ⁵⁾ **Tape and Reel:** All dimensions and tolerances are specified acc. IEC 60286-3 and specified in mm.



BPW 34 SR

Revision History				
Version	Date	Change		
1.5	2020-01-07	Characteristics Electro - Optical Characteristics (Diagrams)		



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